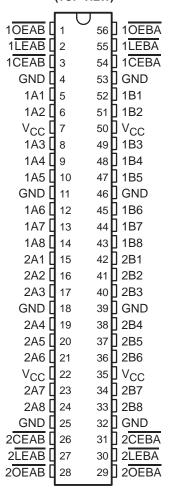
- **Members of the Texas Instruments** Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- **3-State True Outputs**
- Flow-Through Architecture Optimizes PCB Layout
- Distributed V_{CC} and GND Pin **Configurations Minimize High-Speed Switching Noise**
- **EPIC** ™ (Enhanced-Performance Implanted CMOS) 1-um Process
- 500-mA Typical Latch-Up Immunity at
- **Package Options Include Plastic Thin** Shrink Small-Outline (DGG) and 300-mil Shrink Small-Outline (DL) Packages Using 25-mil Center-to-Center Pin Spacings, and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center **Pin Spacings**

description

The 'ACT16543 are 16-bit registered transceivers that contain two sets of D-type latches for temporary storage of data flowing in either direction. The 'ACT16543 can be used as two 8-bit transceivers or one 16-bit transceiver. Separate latch enable (LEAB or LEBA) and output-enable (OEAB or OEBA) inputs are provided for each register to permit independent control in either direction of data flow.

The A-to-B enable (CEAB) and OEAB inputs must be low to enter data from A or to output data to B. Having CEAB low and LEAB low makes the A-to-B latches transparent; a subsequent low-tohigh transition at LEAB puts the A latches in the storage mode. Data flow from B to A is similar, but requires using the CEBA, LEBA, and OEBA inputs.

54ACT16543...WD PACKAGE 74ACT16543 . . . DGG OR DL PACKAGE (TOP VIEW)



The 74ACT16543 is packaged in TI's shrink small-outline package, which provides twice the functionality of standard small-outline packages in the same printed-circuit-board area.

The 54ACT16543 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74ACT16543 is characterized for operation from -40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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54ACT16543, 74ACT16543 16-BIT REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS SCAS126B - MARCH 1990 - REVISED APRIL 1996

FUNCTION TABLE (each octal register)

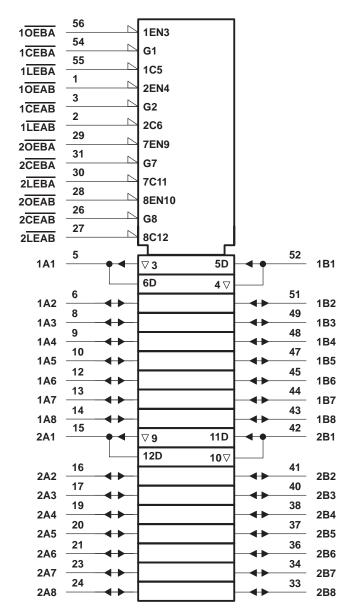
	INPUTS		LATCH STATUS	OUTPUT BUFFERS
CEAB	LEAB	OEAB	A TO BT	B1-B8
Н	Х	Х	Storing	Z
Х	Н	Χ	Storing	
Х	Χ	Н		Z
L	L	L	Transparent	Current A data
L	Н	L	Storing	Previous A data [‡]

[†] A-to-B data flow is shown: B-to-A flow control is the same except that it uses CEBA, LEBA, and OEBA.



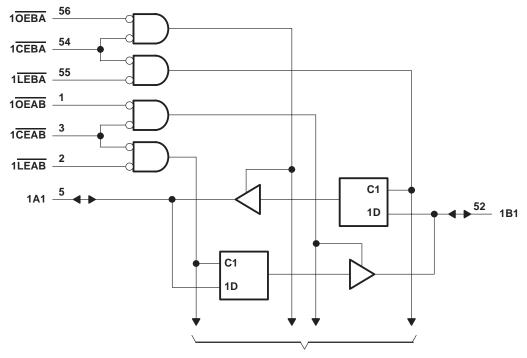
[‡] Data present before low-to-high transition of LEAB occurring while CEAB is low

logic symbol†

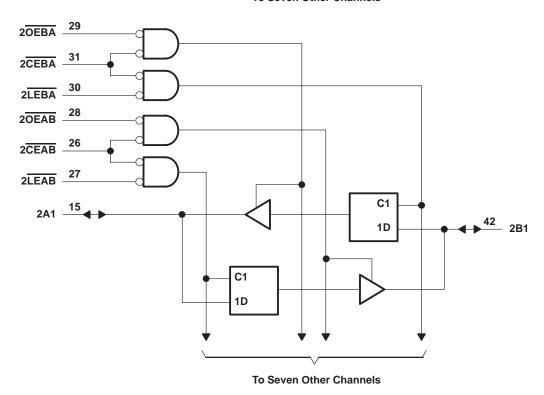


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	0.5 V to V _{CC} +0.5 V
Output voltage range, VO (see Note 1)	0.5 V to V _{CC} +0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V _{CC} or GND	±400 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see No	te 2): DGG package 1 W
	DL package 1.4 W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

		54ACT16543			74ACT16543			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage (see Note 4)	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2		7	2			V
V _{IL}	Low-level input voltage		Š	0.8			0.8	V
٧ _I	Input voltage	0	27	VCC	0		VCC	V
Vo	Output voltage	0	7	VCC	0		VCC	V
ІОН	High-level output current		2	-24			-24	mA
loL	Low-level output current	0	5	24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	-55		125	-40		85	°C

NOTES: 3. Unused pins (inputs and I/O) must be held high or low to prevent them from floating.

4. All V_{CC} and GND pins must be connected to the proper voltage power supply.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

54ACT16543, 74ACT16543 16-BIT REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	Vaa	T,	_Δ = 25°C		54ACT	16543	74ACT	16543	UNIT	
		TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT	
		Jour 50	4.5 V	4.4			4.4		4.4			
		IOH = -50 μA	5.5 V	5.4			5.4		5.4			
Voн		1011 - 24 mA	4.5 V	3.94			3.8		3.8		V	
		$I_{OH} = -24 \text{ mA}$	5.5 V	4.94			4.8		4.8			
		$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85	N	3.85	3.85		
		lo 50A	4.5 V			0.1		0.1		0.1		
		ΙΟΣ = 50 μΑ	5.5 V			0.1	4	0.1		0.1	V	
VOL		I _{OL} = 24 mA	4.5 V			0.36	, C	0.44		0.44		
		10L = 24 IIIA	5.5 V			0.36	70	0.44		0.44		
		$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V				³ PO	1.65		1.65		
Ц	Control inputs	V _I = V _{CC} or GND	5.5 V			±0.1	7	±1		±1	μΑ	
loz	A or B ports [‡]	V _O = V _{CC} or GND	5.5 V			±0.5		±5		±5	μΑ	
Icc		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80		80	μΑ	
Δlcc§		One input at 3.4 V, Other inputs at GND or V _{CC}	5.5 V			0.9		1		1	mA	
Ci	Control inputs	$V_I = V_{CC}$ or GND 5 V 4.5					pF					
C _{io}	A or B ports	$V_O = V_{CC}$ or GND	5 V		12					·	ы	

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		T _A = 25°C		54ACT16543		74ACT16543		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t _W	Pulse duration, LEAB or LEBA low	7.5		7.5	Ling.	7.5		ns
t _{su}	Setup time, data before LEAB or LEBA↑	2.5		2.5	N. C.	2.5		ns
th	Hold time, data after LEAB or LEBA↑	4		4		4		ns

[‡] For I/O ports, the parameter IOZ includes the input leakage current.

[§] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

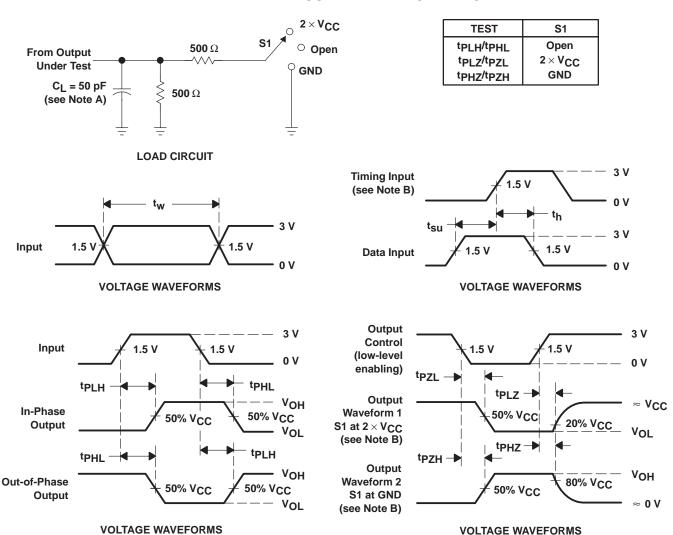
switching characteristics over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	λ = 25°C	;	54ACT	16543	74ACT	16543	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
t _{PLH}	A or B	B or A	3.5	6.9	9.5	3.5	10.5	3.5	10.5	ns
tPHL		BOIA	3.1	7.3	10.7	3.1	11.6	3.1	11.6	115
^t PLH	LEBA or LEAB	A or B	3.9	8.6	12.3	3.9	13.8	3.9	13.8	ns
t _{PHL}		AUIB	3.9	8.7	12.2	3.9	13.5	3.9	13.5	115
^t PZH	OEBA or OEAB	A or B	2.6	7.1	10.3	2.6	11.4	2.6	11.4	ns
tPZL			3.5	8.3	11.9	3.5	13.2	3.5	13.2	115
t _{PHZ}	OEBA or OEAB	A or B	4.1	8.2	10.5	4.1	11.1	4.1	11.1	ns
t _{PLZ}	OEBA OI OEAB	AOIB	5	7.3	9.3	0 5	9.6	5	9.6	115
^t PZH	CEDA 27 CEAD	A or B	3.1	7.3	10.7	3.1	11.7	3.1	11.7	ns
t _{PZL}	CEBA or CEAB		3.9	8.5	12.2	3.9	13.5	3.9	13.5	115
^t PHZ	CEBA or CEAB	A or B	4.6	8.5	11	4.6	11.6	4.6	11.6	ns
t _{PLZ}	CEDA OF CEAB	AUID	5.2	7.4	9.7	5.2	10.5	5.2	10.5	115

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER			TEST CO	TYP	UNIT
C _{pd} Power dissipation capacitance per transceiver	Outputs enabled	C _I = 50 pF, f = 1 MHz		45	~F
	Outputs disabled	CL = 50 pr,	I = I IVINZ	12	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f = 3$ ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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